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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Masahiko Kawase
Serial No.: 10/629,092
Filed: July 28, 2003
For: METHOD OF PRODUCING
CHIP THERMISTOR
Group Art Unit: 3729
Examiner: Unknown
Attorney Docket: MURT P095X1

CERTIFICATE OF MAILING

Date of Deposit: August 9, 2004

I hereby certify that this correspondence is, on the date shown above, being:

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**INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 C.F.R. §1.56 AND §§1.97-1.98**

Commissioner for Patents
Alexandria, Virginia 22313

Sir:

The following Form 1449 and copies of documents listed thereon are being filed herewith as a Disclosure Statement. Consideration of each of these documents by the Patent Examiner, and the making of each of them of record in the file of this application, are respectfully requested.

Each item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign

application not more than three months prior to the filing of this statement. A copy of this communication is also being submitted simultaneously herewith.

Documents J and K were each cited for disclosing an electronic component having a thermistor and a resistor compounded together. Documents L and M were each cited for disclosing a resistor formed inside a layered structure.

Respectfully submitted,



Keiichi Nishimura
Registration No. 29,093

August 9, 2004
BEYER WEAVER & THOMAS, LLP
P.O. Box 778
Berkeley, CA 94704-0778
Telephone: (510) 843-6200
Telefax: (510) 843-6203



Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. MURT P095X1	Application No.: 10/629,092
	Applicant: Masahiko Kawase Filing Date July 28, 2003	Group 3729

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J	9-69418	03/11/97	JP				X
	K	2-189901	07/25/90	JP				X
	L	3-60148	03/15/91	JP				X
	M	5-275958	10/22/93	JP				X
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	O	
	P	
	Q	
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.